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PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**Applicant(s):** Reginald R. Bowley, et al. **Examiner:** Unassigned**Serial No:** Unassigned**Art Unit:** Unassigned**Filed:** Herewith**Docket:** BUR920010128US1(15015)**For:** CONTACT HOLE PROFILE AND  
LINE EDGE WIDTH METROLOGY FOR  
CRITICAL IMAGE CONTROL AND FEEDBACK  
OF LITHOGRAPHIC FOCUS**Dated:** February 5, 2002Assistant Commissioner for Patents  
Washington, D.C. 20231INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.97 and 1.98, it is requested that the following references, which are also listed on the attached Form PTO-1449, be made of record in the above-identified case.

1. U.S. Patent No. 5,532,090, dated July 2, 1996, issued to Borodovsky;
2. U.S. Patent No. 5,914,784, dated June 22, 1999, issued to Ausschnitt, et al.;
3. U.S. Patent No. 5,756,238, dated May 26, 1998, issued to Barr, et al.;
4. U.S. Patent No. 6,021,009, dated February 1, 2000, issued to Borodovsky, et al.;
5. U.S. Patent No. 6,027,842, dated February 22, 2000, issued to Ausschnitt, et al.;
6. U.S. Patent No. 6,049,660, dated April 11, 2000, issued to Ahn, et al.;
7. U.S. Patent No. 6,190,810 B1, dated February 20, 2001, issued to Lai, et al.;

8. Japanese Laid-Open Publication No. JP 6-294625, dated October 21, 1994, together with English Language Abstract,
9. Japanese Laid-Open Publication No. JP 11-186132, dated July 9, 1999, together with English Language Abstract,
10. Japanese Laid-Open Publication No. JP 2000-12426, dated January 14, 2000, together with English Language Abstract,

Applicants are submitting copies of the above-cited references.

Inasmuch as this Information Disclosure Statement is being submitted in accordance with the schedule set out in 37 C.F.R. § 1.97(b), no statement or fee is required.

Respectfully submitted,

  
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